## MSKSEMI















**ESD** 

TVS

TSS

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**GDT** 

**PLED** 

# Brodnet data speet

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TRANSISTOR (NPN)

**FEATURE** 

power switching applications

**SOT - 23** 

1. BASE 2. EMITTER

3. COLLECTOR

MAXIMUM RATINGS (Ta=25°C unless otherwise noted)

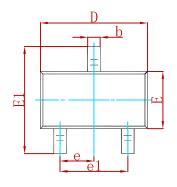
Symbol	Parameter	Value	Unit
V <sub>CBO</sub>	Collector -Base Voltage	700	V
V <sub>CEO</sub>	Collector-Emitter Voltage	400	V
V <sub>EBO</sub>	Emitter-Base Voltage	9	V
Ic	Collector Current -Continuous	0.2	Α
Pc	Collector Power Dissipation	0.35	W
T <sub>J</sub>	Junction Temperature	150	°C
T <sub>stg</sub>	Storage Temperature	-55~150	$^{\circ}$

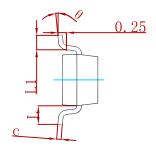
#### **ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)**

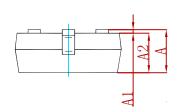
Parameter	Symbol	Test conditions	Min	Тур	Max	Unit
Collector-base breakdown voltage	V <sub>(BR)CBO</sub>	I <sub>C</sub> = 1mA ,I <sub>E</sub> =0	700			V
Collector-emitter breakdown voltage	V <sub>(BR)CEO</sub>	I <sub>C</sub> = 1mA ,I <sub>B</sub> =0	400			V
Emitter-base breakdown voltage	V <sub>(BR)EBO</sub>	I <sub>E</sub> = 100μA, I <sub>C</sub> =0	9			V
Collector cut-off current	I <sub>CBO</sub>	V <sub>CB</sub> = 600V , I <sub>E</sub> =0			10	μΑ
Emitter cut-off current	I <sub>EBO</sub>	V <sub>EB</sub> =9V, I <sub>C</sub> =0			10	μΑ
DC current gain	h <sub>FE(1)</sub>	V <sub>CE</sub> = 10V, I <sub>C</sub> = 20mA	10		40	
DC current gain						
Collector-emitter saturation voltage	$V_{CE(sat)}$	I <sub>C</sub> = 100mA, I <sub>B</sub> = 20 mA			0.5	V
Base-emitter saturation voltage	$V_{BE(sat)}$	I <sub>C</sub> = 100mA, I <sub>E</sub> = 20mA			1.2	٧
Transition frequency	f <sub>T</sub>	$V_{CE}$ = 20V, $I_{C}$ =20mA $f$ = 1MHz	5			MHz
Storage time	t <sub>S</sub>	Ic=100mA			3.5	μs



#### **PACKAGE MECHANICAL DATA**

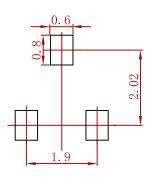






Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
Е	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.03	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

#### **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
MS13001	SOT-23	3000



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